



CPH3140 / CPH3240 — High-Voltage Switching Applications

PNP / NPN Epitaxial Planar Silicon Transistors

Features

- Adoption of FBIT, MBIT processes
- High breakdown voltage and large current capacity
- High-speed switching
- Ultrasmall size making it easy to provide high-density, small-sized hybrid ICs

Specifications () : CPH3140

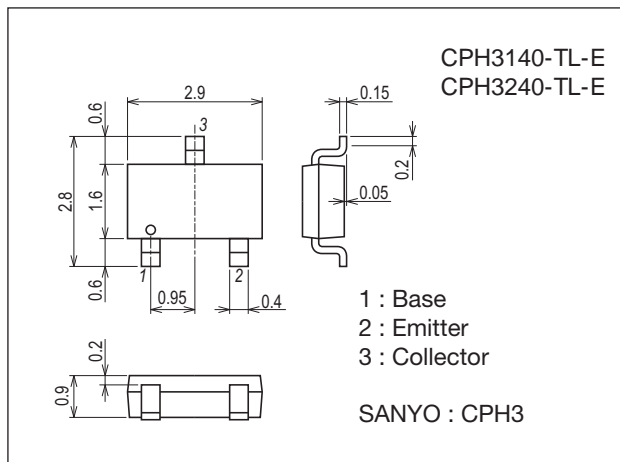
Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Collector-to-Base Voltage	V _{CB0}		(-)120	V
Collector-to-Emitter Voltage	V _{CEO}		(-)100	V
Emitter-to-Base Voltage	V _{EBO}		(-)6	V
Collector Current	I _C		(-)1	A
Collector Current (Pulse)	I _{CP}		(-)2	A
Collector Dissipation	P _C	When mounted on ceramic substrate (600mm ² ×0.8mm)	0.9	W
Junction Temperature	T _J		150	°C
Storage Temperature	T _{stg}		-55 to +150	°C

Package Dimensions

unit : mm (typ)

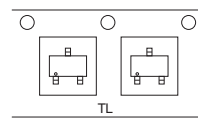
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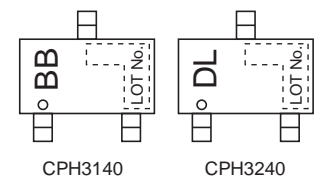
Product & Package Information

- Package : CPH3
- JEITA, JEDEC : SC-59, TO-236, SOT-23
- Minimum Packing Quantity : 3,000 pcs./reel

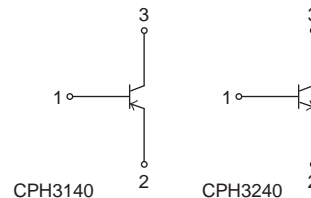
Packing Type: TL



Marking



Electrical Connection

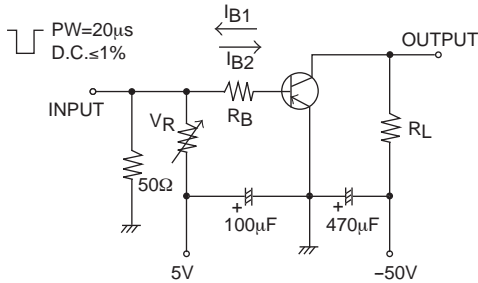


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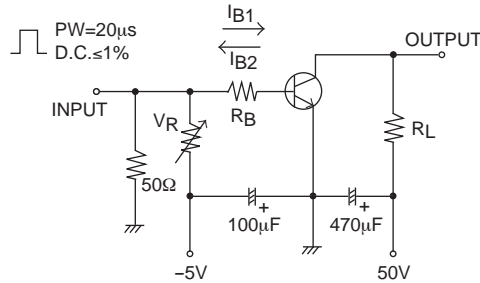
Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector Cutoff Current	ICBO	V _{CB} =(-)100V, I _E =0A			(-) 100	nA
Emitter Cutoff Current	IEBO	V _{EB} =(-)4V, I _C =0A			(-) 100	nA
DC Current Gain	h _{FE}	V _{CE} =(-)5V, I _C =(-)100mA	140		400	
Gain-Bandwidth Product	f _T	V _{CE} =(-)10V, I _C =(-)100mA		120		MHz
Output Capacitance	C _{ob}	V _{CB} =(-)10V, f=1MHz		(13)8.5		pF
Collector-to-Emitter Saturation Voltage	V _{CE(sat)}	I _C =(-)400mA, I _B =(-)40mA		(-0.2)0.1	(-0.6)0.4	V
Base-to-Emitter Saturation Voltage	V _{BE(sat)}	I _C =(-)400mA, I _B =(-)40mA		(-)0.85	(-)1.2	V
Collector-to-Base Breakdown Voltage	V _{(BR)CBO}	I _C =(-)10μA, I _E =0A	(-)120			V
Collector-to-Emitter Breakdown Voltage	V _{(BR)CEO}	I _C =(-)1mA, R _{BE} =∞	(-)100			V
Emitter-to-Base Breakdown Voltage	V _{(BR)EBO}	I _E =(-)10μA, I _C =0A	(-)6			V
Turn-On Time	t _{on}	See specified Test Circuit.		(80)80		ns
Storage Time	t _{stg}			(700)850		ns
Fall Time	t _f			(40)50		ns

Switching Time Test Circuit



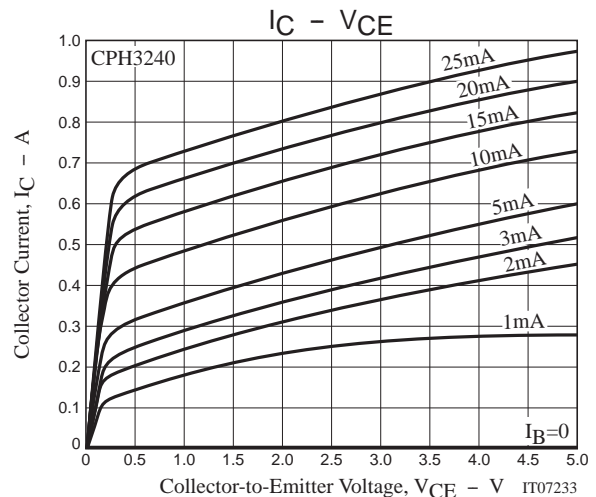
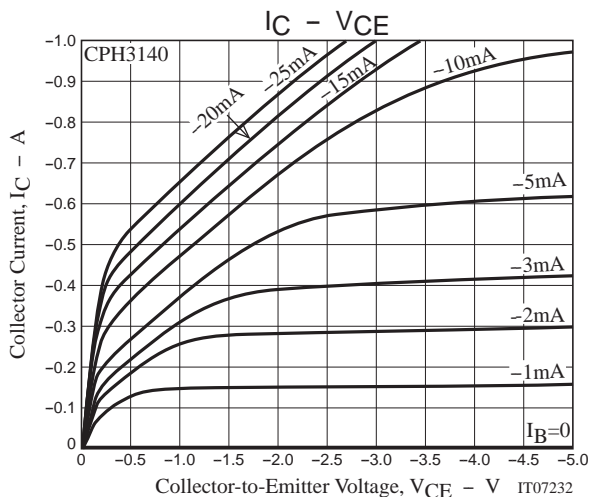
IC = -10IB1 = 10IB2 = -400mA
CPH3140



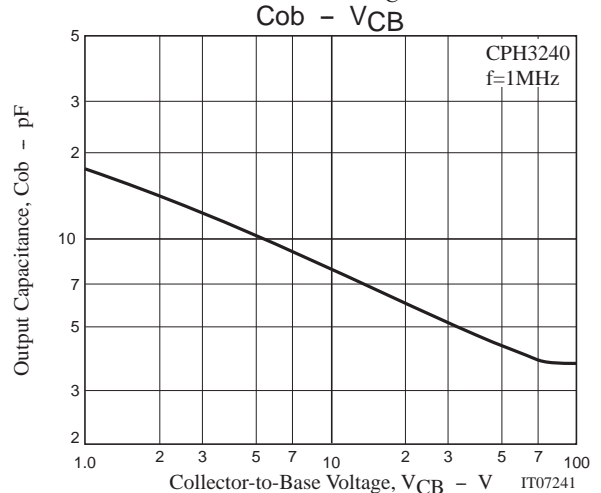
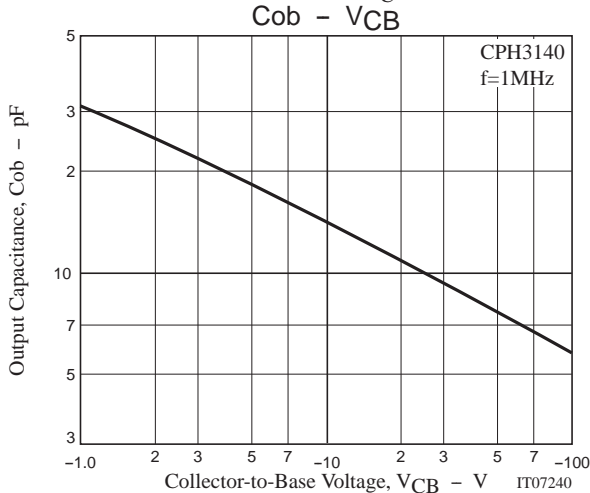
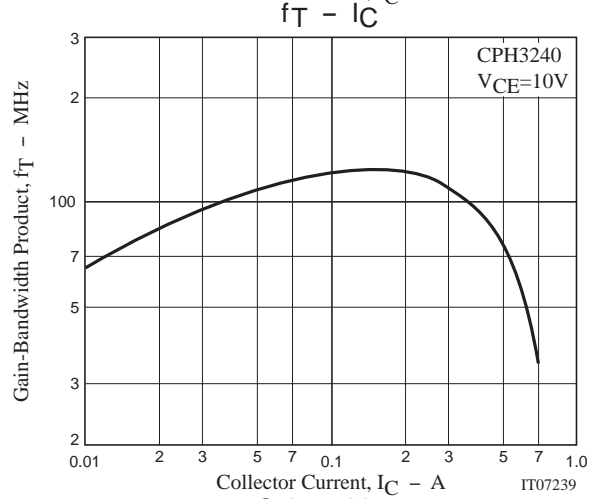
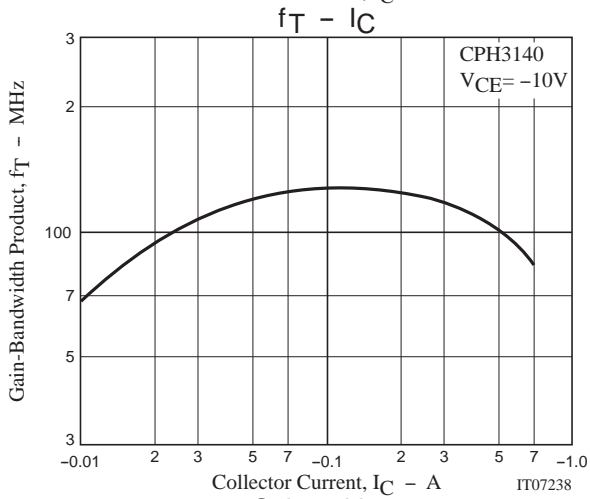
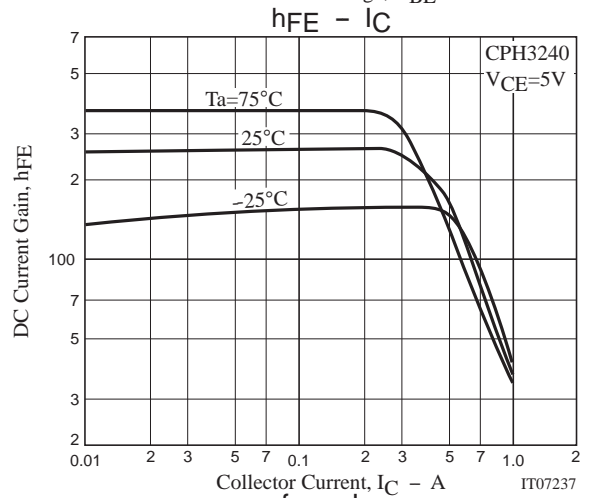
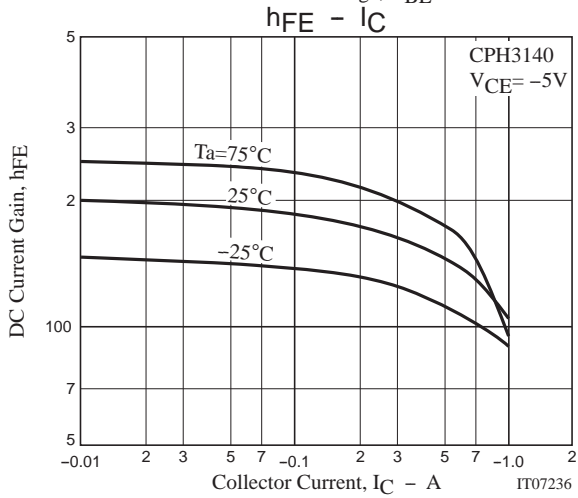
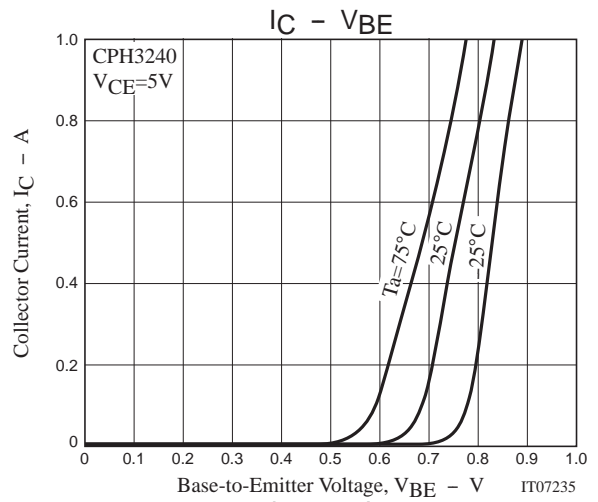
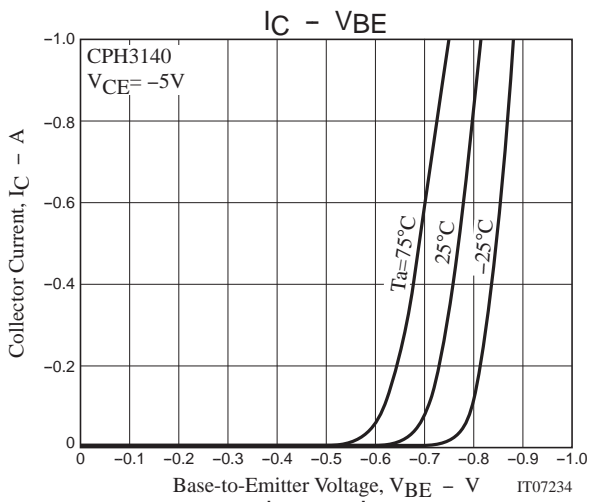
IC = 10IB1 = -10IB2 = 400mA
CPH3240

Ordering Information

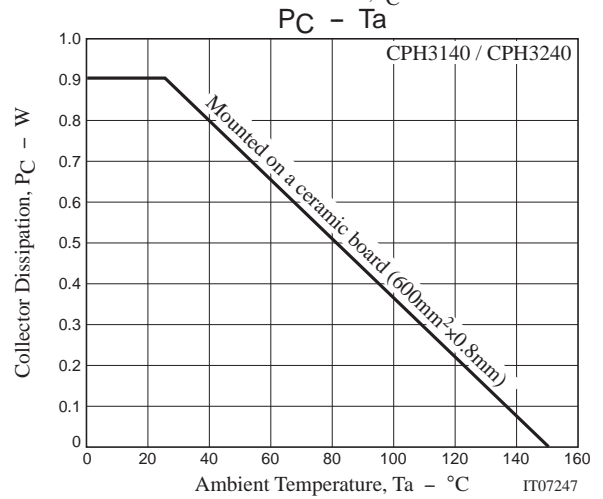
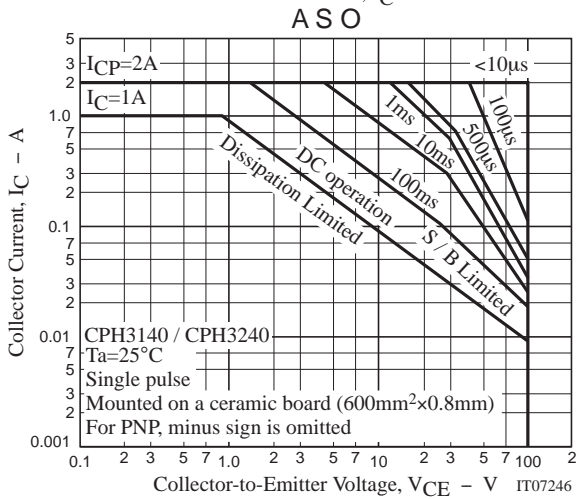
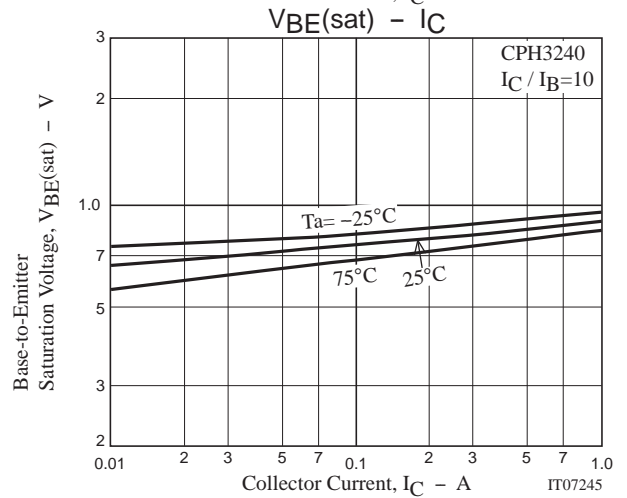
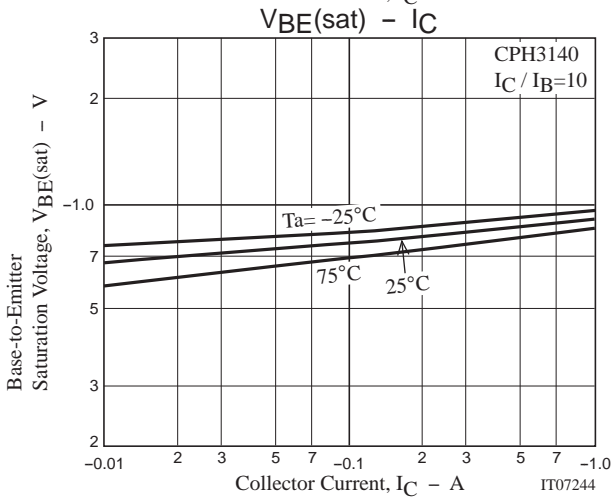
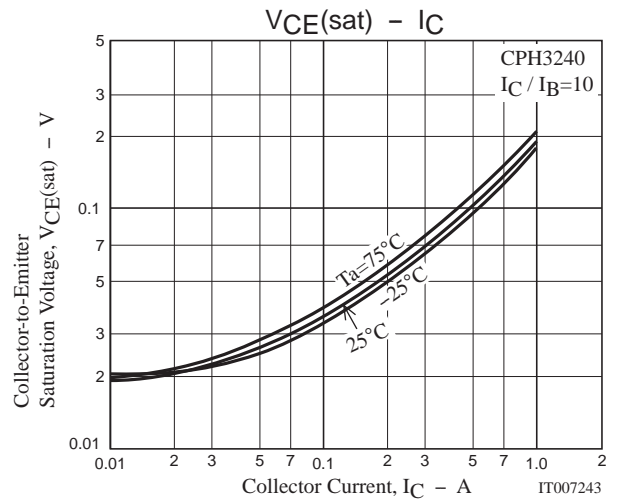
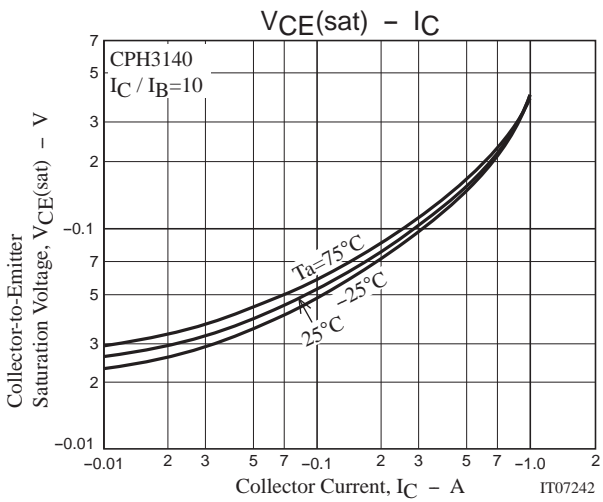
Device	Package	Shipping	memo
CPH3140-TL-E	CPH3	3,000pcs./reel	Pb Free
CPH3240-TL-E	CPH3	3,000pcs./reel	Pb Free



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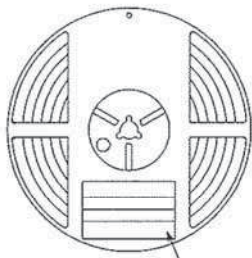
Embossed Taping Specification

CPH3140-TL-E, CPH3240-TL-E

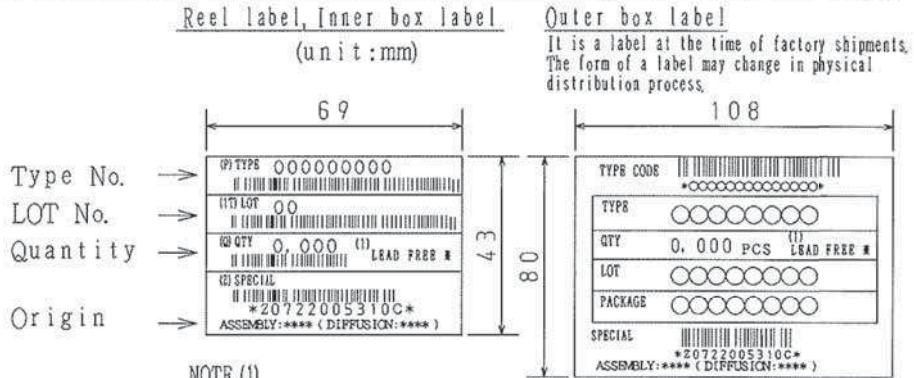
1. Packing Format

Package Name	Carrier Tape Type	Maximum Number of devices contained (pcs)			Packing format	
		Reel	Inner box	Outer box	Inner BOX (C-1)	Outer BOX (A-7)
CPH3	CPH3	3,000	15,000	90,000	5 reels contained Dimensions:mm (external) 183×72×185	6 inner boxes contained Dimensions:mm (external) 440×195×210

Packing method



Reel label



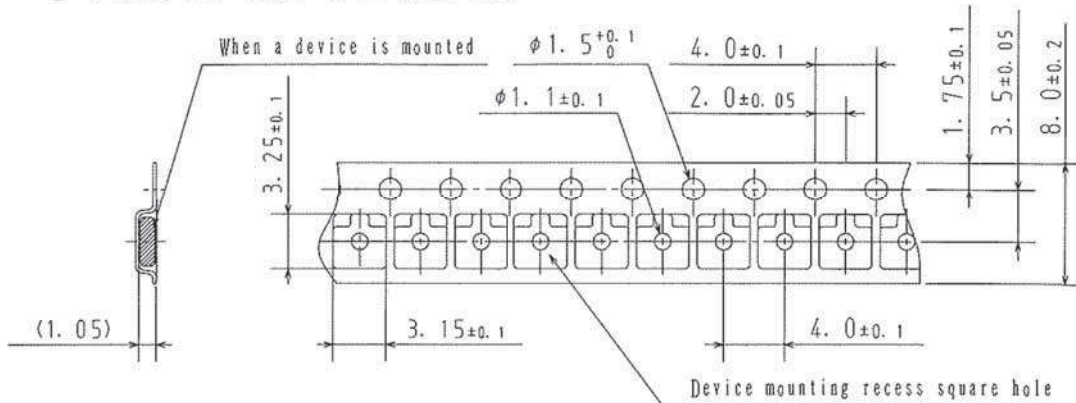
NOTE (1)

The LEAD FREE # description shows that the surface treatment of the terminal is lead free.

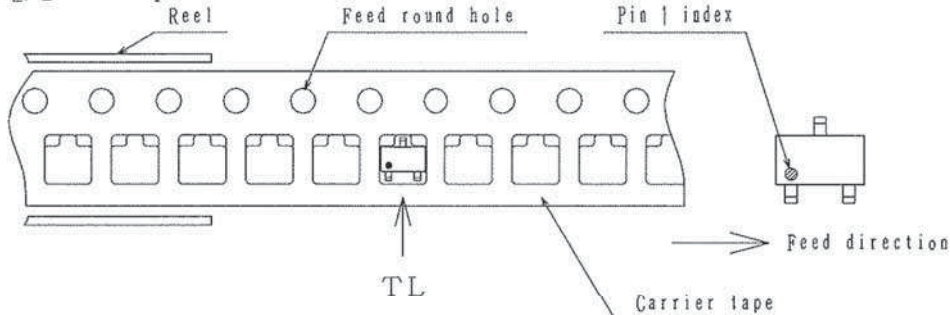
Label	JEITA Phase
LEAD FREE 3	JEITA Phase 3A
LEAD FREE 4	JEITA Phase 3

2. Taping configuration

2-1. Carrier tape size (unit:mm)



2-2. Device placement direction

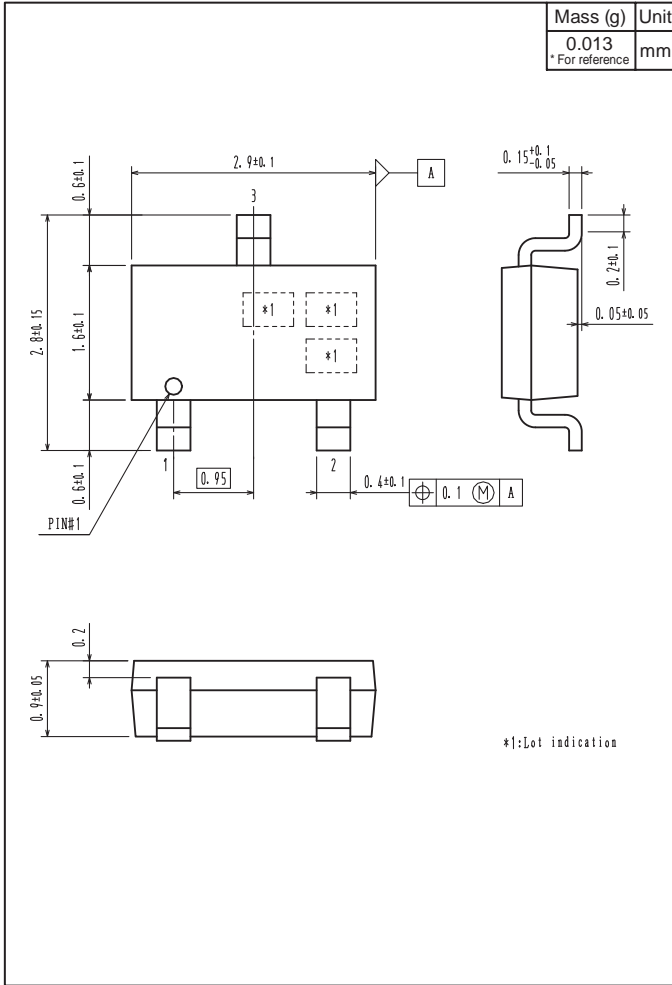


Those with one electrode terminal on the feed hole side.....TL

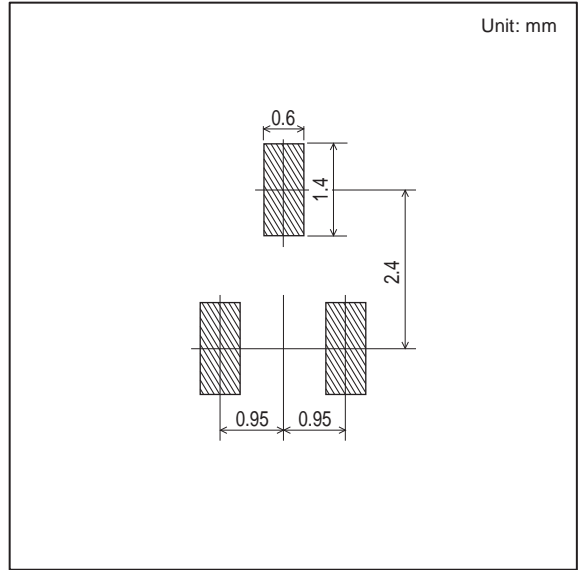
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Outline Drawing

CPH3140-TL-E, CPH3240-TL-E



Land Pattern Example



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